



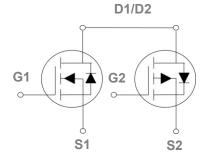
# Product data sheet

www.msksemi.com



# **TO252-4** Pin Configuration





#### **Features**

- Fast switching
- Green Device Available
- Suit for 4.5V Gate Drive Applications

#### **Applications**

- DC Fan
- Motor Drive Applications
- Networking
- Half / Full Bridge Topology

BVDSS	RDSON	ID
40V	19m $\Omega$	15A
-40V	$38 m\Omega$	-12A

#### Absolute Maximum Ratings Tc=25°C unless otherwise noted

Symbol	Symbol Parameter Rating		Units	
V <sub>DS</sub>	Drain-Source Voltage	40	-40	V
V <sub>GS</sub>	Gate-Source Voltage	±20	±20	V
	Drain Current – Continuous (T <sub>C</sub> =25°C)	15	-12	A
ID	Drain Current – Continuous (T <sub>C</sub> =100°C)	9	-7	A
I <sub>DM</sub>	Drain Current – Pulsed <sup>1</sup>	60	-48	A
D	Power Dissipation (T <sub>c</sub> =25°C)	20	)	W
PD	Power Dissipation – Derate above 25°C	0.1	6	W/°C
T <sub>STG</sub>	Storage Temperature Range	-55 to	-55 to 150	
TJ	Operating Junction Temperature Range	-55 to	-55 to 150	

#### **Thermal Characteristics**

Symbol	Symbol Parameter		Max.	Unit
R <sub>θJC</sub>	Thermal Resistance Junction to Case		6	°C/W
R <sub>0JA</sub>	Thermal Resistance Junction to Ambient		62	°C/W





# **N-CH Electrical Characteristics** (T<sub>J</sub>=25 °C, unless otherwise)

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	40			V
0BV <sub>DSS</sub> /0T <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient	Reference to $25^{\circ}$ C , I <sub>D</sub> =1mA		0.04		V/°C
	Drain Source Lookage Current	$V_{\text{DS}}\text{=}40V$ , $V_{\text{GS}}\text{=}0V$ , $T_{\text{J}}\text{=}25^{\circ}\text{C}$			1	uA
IDSS	Drain-Source Leakage Current	$V_{\text{DS}}\text{=}32\text{V}$ , $V_{\text{GS}}\text{=}0\text{V}$ , $T_{\text{J}}\text{=}125^{\circ}\text{C}$			10	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}$ =±20V , $V_{DS}$ =0V			±100	nA

#### **On Characteristics**

Б	R <sub>DS(ON)</sub> Static Drain-Source On-Resistance	V <sub>GS</sub> =10V , I <sub>D</sub> =6A		19	30	mΩ
NDS(ON)		V <sub>GS</sub> =4.5V , I <sub>D</sub> =4A		30	42	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	-V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1.0	1.5	2.5	V
OV <sub>GS(th)</sub>	V <sub>GS(th)</sub> Temperature Coefficient	VGS-VDS, ID -2500A		-3		mV/°C
gfs	Forward Transconductance	V <sub>DS</sub> =10V , I <sub>D</sub> =3A		6.5		S

#### **Dynamic and switching Characteristics**

Qg	Total Gate Charge <sup>2,3</sup>		 5.2	
Q <sub>gs</sub>	Gate-Source Charge <sup>2,3</sup>	$V_{\text{DS}}\text{=}20V$ , $V_{\text{GS}}\text{=}4.5V$ , $I_{\text{D}}\text{=}6A$	 1.2	nC
Q <sub>gd</sub>	Gate-Drain Charge <sup>2 , 3</sup>		 2.5	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2 , 3</sup>		 3.2	
Tr	Rise Time <sup>2 , 3</sup>	$V_{DD}\texttt{=}\texttt{2}0V$ , $V_{GS}\texttt{=}\texttt{4}.5V$ , $R_{G}\texttt{=}\texttt{2}5\Omega$	 8.6	20
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2 , 3</sup>	I <sub>D</sub> =1A	 18	ns
T <sub>f</sub>	Fall Time <sup>2 , 3</sup>		 6	
C <sub>iss</sub>	Input Capacitance		 420	
C <sub>oss</sub>	Output Capacitance	$V_{DS}$ =15V , $V_{GS}$ =0V , F=1MHz	 65	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		 40	

#### **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current				15	А
I <sub>SM</sub>	Pulsed Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			30	А
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1	V

Note :

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.

2. The data tested by pulsed , pulse width  $\leq 300 \text{us}$  , duty cycle  $\leq 2\%.$ 

3. Essentially independent of operating temperature.





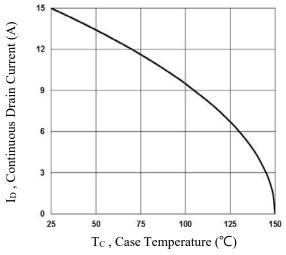
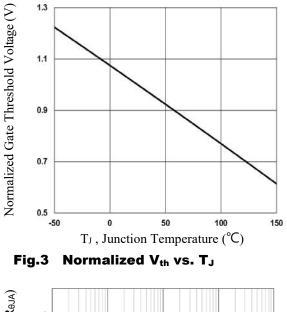
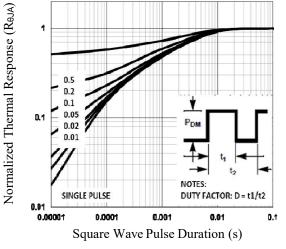
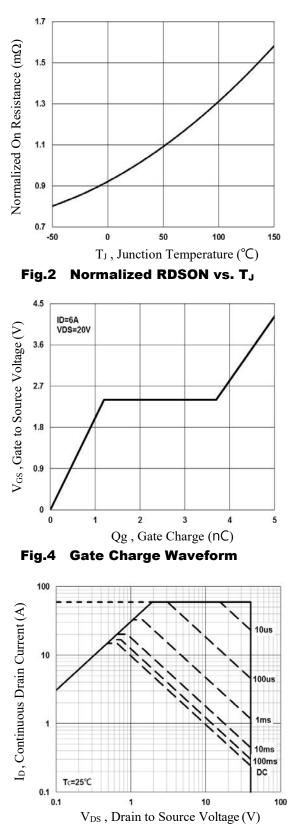


Fig.1 Continuous Drain Current vs. Tc









**Fig.6 Maximum Safe Operation Area** 





# P-CH Electrical Characteristics (TJ=25 °C, unless otherwise

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-40			V
$\Delta BV_{DSS}/\Delta T_{J}$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C,I <sub>D</sub> =-1mA		-0.04		V/°C
	Drain Sauras Laskana Cumant	$V_{DS}$ =-40V , $V_{GS}$ =0V , $T_{J}$ =25°C			-1	uA
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =-32V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			-10	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}$ =±10V , $V_{DS}$ =0V			±100	nA

#### **On Characteristics**

R <sub>DS(ON)</sub> Static Drain-Source On-Resistance	Static Drain Source On Posiciance	V <sub>GS</sub> =-10V , I <sub>D</sub> =-5A		38	45	mΩ
	$V_{GS}$ =-4.5V , $I_D$ =-3A		45	70	mΩ	
V <sub>GS(th)</sub>	Gate Threshold Voltage		-1.0	<b>-</b> 1.5	<b>-</b> 2.5	V
∆V <sub>GS(th)</sub>	V <sub>GS(th)</sub> Temperature Coefficient	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250uA		3		mV/°C
gfs	Forward Transconductance	V <sub>DS</sub> =-10V , I <sub>D</sub> =-3A		9		S

#### **Dynamic and switching Characteristics**

Qg	Total Gate Charge <sup>2 , 3</sup>		 9	
$Q_gs$	Gate-Source Charge <sup>2 , 3</sup>	V <sub>DS</sub> =-20V , V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-5A	 2.5	nC
Q <sub>gd</sub>	Gate-Drain Charge <sup>2 , 3</sup>		 3.2	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2 , 3</sup>		 20	
Tr	Rise Time <sup>2 , 3</sup>	$V_{\text{DD}}$ =-20V , $V_{\text{GS}}$ =-4.5V , $R_{\text{G}}$ =25 $\Omega$	 12	20
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2 , 3</sup>	I <sub>D</sub> =-1A	 46	ns
T <sub>f</sub>	Fall Time <sup>2 , 3</sup>		 6	
Ciss	Input Capacitance		 1050	
Coss	Output Capacitance	V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , F=1MHz	 110	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		 80	

#### **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-12	А
I <sub>SM</sub>	Pulsed Source Current	VG-VD-OV, FOICe Cullent			-24	А
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25°C			-1	V

Note :

4. Repetitive Rating : Pulsed width limited by maximum junction temperature.

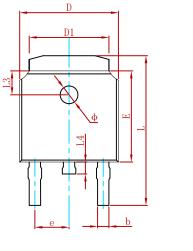
5. The data tested by pulsed , pulse width  $\leq 300 \text{us}$  , duty cycle  $\leq 2\%.$ 

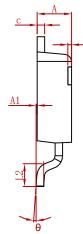
6. Essentially independent of operating temperature.



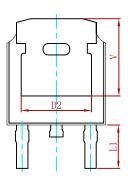


# PACKAGE MECHANICAL DATA



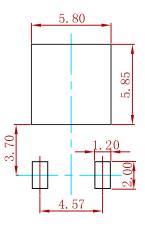


h



Symbol	Dimensions	In Millimeters	Dimension	s In Inches	
Symbol	Min.	Max.	Min.	Max.	
A	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.635	0.770	0.025	0.030	
С	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	4.830	REF.	0.190	REF.	
E	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.712	10.312	0.382	0.406	
L1	2.900	REF.	0.114	REF.	
L2	1.400	1.700	0.055	0.067	
L3	1.600	REF.	0.063	REF.	
L4	0.600	1.000	0.024	0.039	
Φ	1.100	1.300	0.043	0.051	
θ	0°	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.250	REF.	0.207 REF.		

# Suggested Pad Layout



Note:

1.Controlling dimension:in millimeters.

2.General tolerance:± 0.05mm.

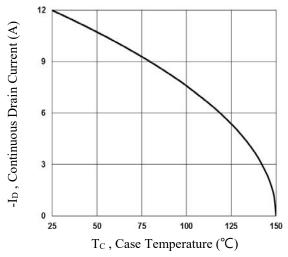
3. The pad layout is for reference purposes only.

## **REEL SPECIFICATION**

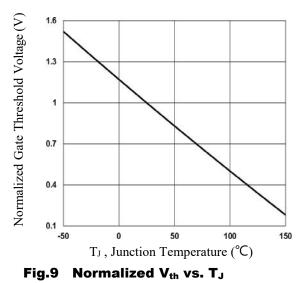
P/N PKG QTY			
	P/N	PKG	QTY
AOD609-MS TO-252-4 2500	AOD609-MS	TO-252-4	2500











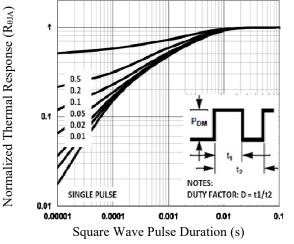


Fig.11 Normalized Transient Impedance

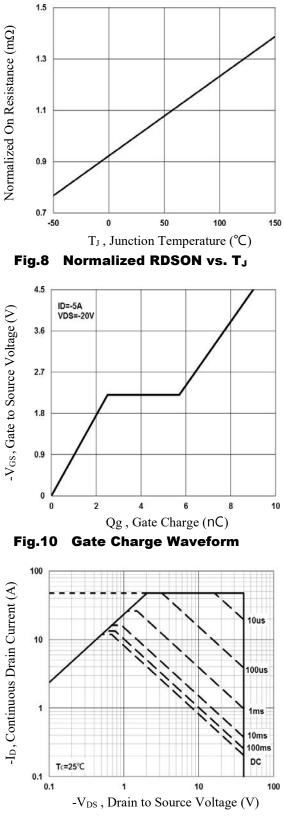


Fig.12 Maximum Safe Operation Area



# <u>Attention</u>

■ Any and all MSKSEMI Semiconductor products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your MSKSEMI Semiconductor representative nearest you before using any MSKSEMI Semiconductor products described or contained herein in such applications.

■ MSKSEMI Semiconductor assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications f any and all MSKSEMI Semiconductor products described orcontained herein.

■ Specifications of any and all MSKSEMI Semiconductor products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.

■ MSKSEMI Semiconductor. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with someprobability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits anderror prevention circuits for safedesign, redundant design, and structural design.

■ In the event that any or all MSKSEMI Semiconductor products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from theauthorities concerned in accordance with the above law.

■ No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of MSKSEMI Semiconductor.

■ Information (including circuit diagrams and circuit parameters) herein is for example only ; it is not guaranteed for volume production. MSKSEMI Semiconductor believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.

Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. Whendesigning equipment, referto the "Delivery Specification" for the MSKSEMI Semiconductor productthat you intend to use.